

# FDG314P

# **Digital FET, P-Channel**

### **General Description**

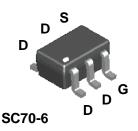
This P-Channel enhancement mode field effect transistor is produced using Fairchild Semiconductor's proprietary, high cell density, DMOS technology. This very high density process is tailored to minimize onstate resistance at low gate drive conditions. This device is designed especially for battery power applications such as notebook computers and cellular phones. This device has excellent on-state resistance even at gate drive voltages as low as 2.5 volts.

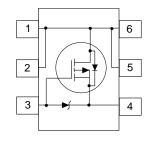
## **Applications**

- Power Management
- Load switch
- Signal switch

### **Features**

- -0.65 A, -25 V.  $R_{DS(ON)} = 1.1 \ \Omega \ @ \ V_{GS} = -4.5 \ V$   $R_{DS(ON)} = 1.5 \ \Omega \ @ \ V_{GS} = -2.7 \ V.$
- Very low gate drive requirements allowing direct operation in 3V cirucuits (V<sub>GS(th)</sub> <1.5 V).</li>
- Gate-Source Zener for ESD ruggedness (>6 kV Human Body Model).
- Compact industry standard SC70-6 surface mount package.





## Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage	-25	V	
V <sub>GSS</sub>	Gate-Source Voltage		±8	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	-0.65	A
	- Pulsed		-1.8	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	0.75	W
		(Note 1b)	0.48	
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperatu	-55 to +150	°C	
ESD	Electrostatic Discharge Rating MIL-STD-88: Human Body Model (100pf/1500 Ohm)	6.0	kV	

### **Thermal Characteristics**

R <sub>e</sub> JA Thermal Resistance, Junction-to-Ambient (Note 1b) 260 °C/W
--

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape Width	Quantity
-14	FDG314P	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics			•	•	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-25			V
$\Delta BV_{DSS} \over \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, Referenced to 25°C		-19		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0 V			-1	μΑ
I <sub>GSS</sub>	Gate-Body Leakage Current	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.65	-0.72	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, Referenced to 25°C		2		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -0.5 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -0.5 \text{ A}$ @ 125°C $V_{GS} = -2.7 \text{ V}, I_D = -0.25 \text{ A}$		0.77 1.08 1.06	1.1 1.8 1.5	Ω
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-1			Α
<b>g</b> FS	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -0.5 \text{ A}$		0.9		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		63		pF
Coss	Output Capacitance	f = 1.0 MHz		34		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			10		pF
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -6 \text{ V}, I_{D} = -0.5 \text{ A},$		7	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ = -4.5 V, $R_{GEN}$ = 50 $\Omega$		8	20	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1		55	110	ns
t <sub>f</sub>	Turn-Off Fall Time	1		35	70	ns
Qg	Total Gate Charge	$V_{DS} = -5 \text{ V}, I_{D} = -0.25 \text{ A},$		1.1	1.5	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -4.5 V		0.32		nC
$Q_{gd}$	Gate-Drain Charge			0.25		nC
Drain-So	urce Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				-0.42	Α
V <sub>SD</sub>	Drain-Source Diode Forward	$V_{GS} = 0 \text{ V}, I_S = -0.42 \text{ A}$ (Note 2)		-0.85	-1.2	V

### Notes:

<sup>1.</sup>  $R_{QJA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{QJC}$  is guaranteed by design while  $R_{QCA}$  is determined by the user's board design.

a) 170°C/W when mounted on a 1 in² pad of 2oz copper.

b) 260°C/W when mounted on a minimum mounting pad.

<sup>2.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%

# **Typical Characteristics**

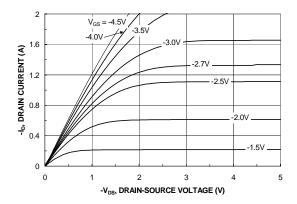


Figure 1. On-Region Characteristics.

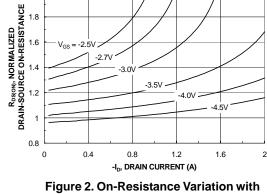


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

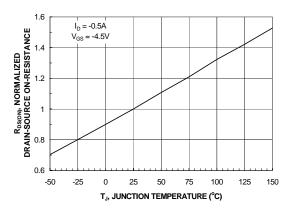


Figure 3. On-Resistance Variation with Temperature.

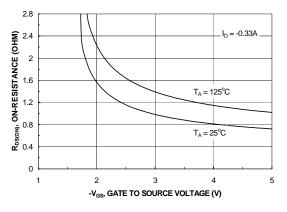


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

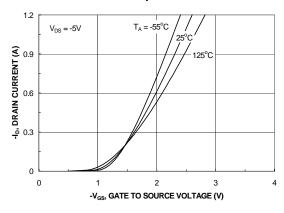


Figure 5. Transfer Characteristics.

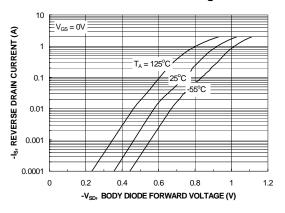
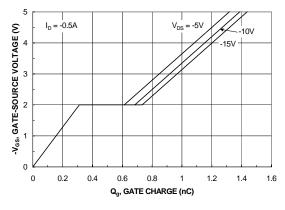


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# Typical Characteristics (continued)



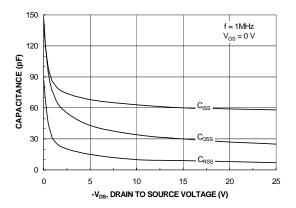
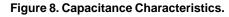
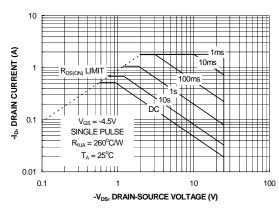


Figure 7. Gate-Charge Characteristics.





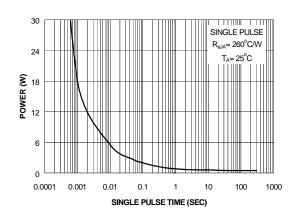


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

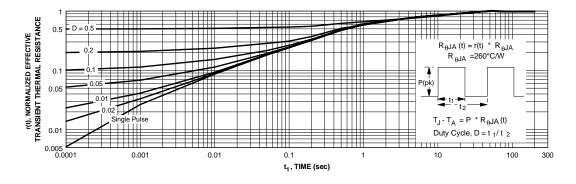
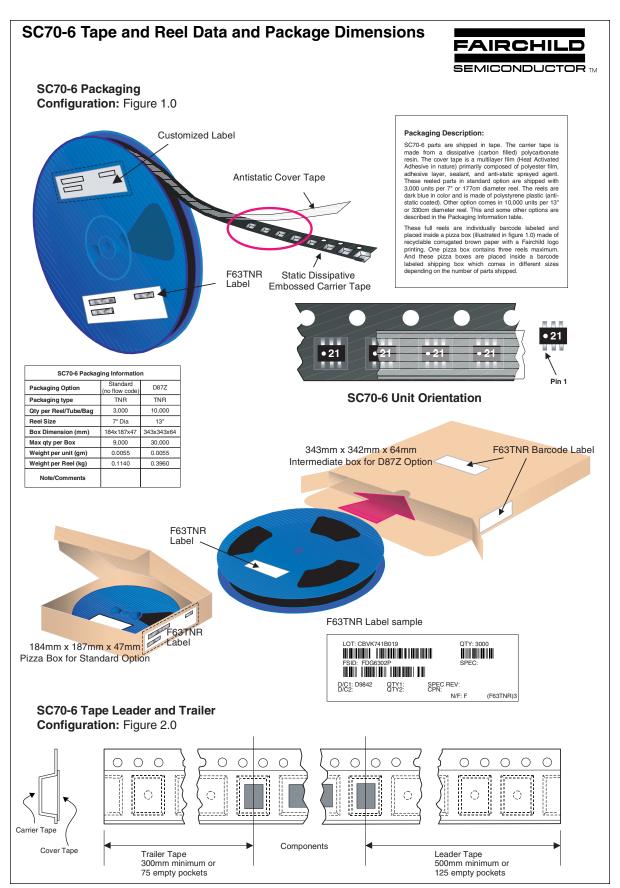


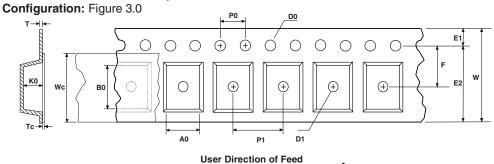
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient themal response will change depending on the circuit board design.





# **SC70-6 Embossed Carrier Tape**

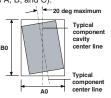


Dimensions are in millimeter														
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SC70-6 (8mm)	2.24 +/-0.10	2.34 +/-0.10	8.0 +/-0.3	1.55 +/-0.05	1.125 +/-0.125	1.75 +/-0.10	6.25 min	3.50 +/-0.05	4.0 +/-0.1	4.0 +/-0.1	1.20 +/-0.10	0.255 +/-0.150	5.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

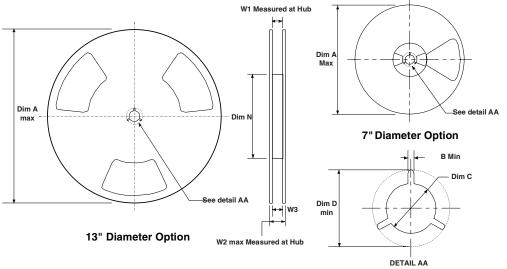


Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

# SC70-6 Reel Configuration: Figure 4.0



Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
8mm	7" Dia	7.00 177.8	0.059 1.5	0.512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.331 +0.059/-0.000 8.4 +1.5/0	0.567 14.4	0.311 - 0.429 7.9 - 10.9
8mm	13" Dia	13.00 330	0.059 1.5	0.512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	4.00 100	0.331 +0.059/-0.000 8.4 +1.5/0	0.567 14.4	0.311 - 0.429 7.9 - 10.9

# SC70-6 Tape and Reel Data and Package Dimensions, continued SC70-6 (FS PKG Code 76) Scale 1:1 on letter size paper Dimensions shown below are in: inches [millimeters] Part Weight per unit (gram): 0.0055 2.00±0.20-0.65 -0.50 MIN 1.25±0.10 1.90 $\mathbb{H}$ (0.25)0.40 MIN **⊕** 0.10**M** A B 0.65 LAND PATTERN RECOMMENDATION 1.30 SEE DETAIL A 0.10 0.10 0 卣 -(0.43)SEATING -2.10±0,30-PLANE GAGE PLANE NOTES: UNLESS OTHERWISE SPECIFIED (R0.10) THIS PACKAGE CONFORMS TO EIAJ SC-8B, 1996. ALL DIMENSIONS ARE IN MILLIMETERS. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. 0.20 DETAIL A MAAO&AREVD

### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEX™ FASTr™ QFET™ VCX™

Bottomless™ GlobalOptoisolator™ QS™

CoolFET™ GTO™ QT Optoelectronics™

CROSSVOLT™ HiSeC™ Quiet Series™ DOME™ ISOPLANAR™ SuperSOT™-3 E<sup>2</sup>CMOS<sup>TM</sup> MICROWIRE™ SuperSOT™-6 OPTOLOGIC™ EnSigna™ SuperSOT™-8 FACT™ OPTOPLANAR™ SyncFET™ POP™ FACT Quiet Series™ TinyLogic™

FAST® PowerTrench® UHC™

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.